

Dielectron Simulations for the CBM-TRD

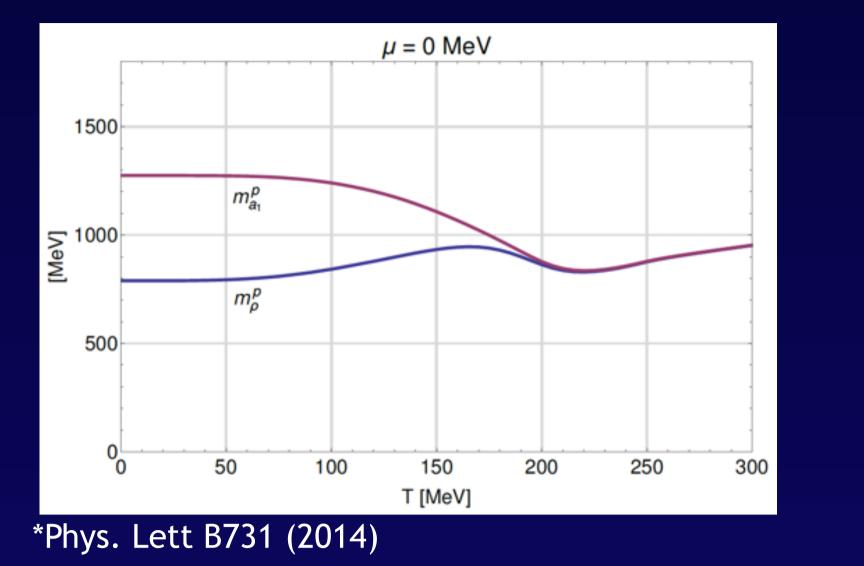
Etienne Bechtel¹ for the CBM-TRD Group

¹ IKF, Frankfurt, Germany

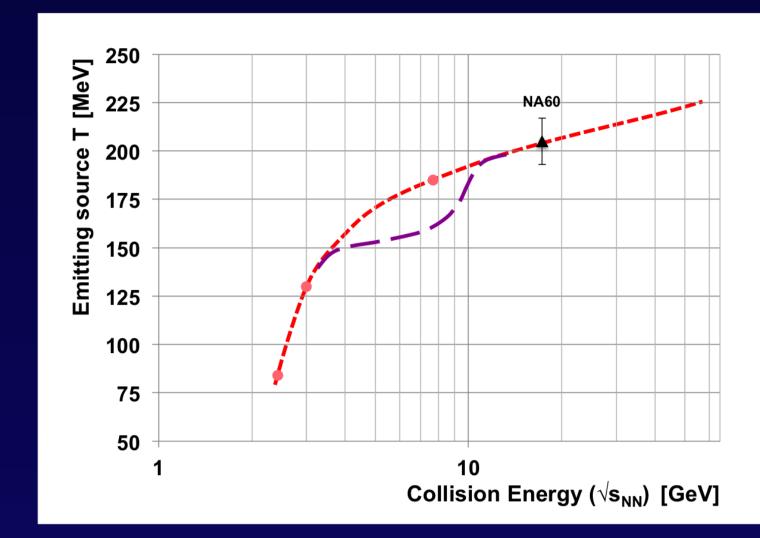
Motivation

- In nature chiral symmetry is spontaneously broken
 - A measurement of it's restoration would be a breakthrough
 - Manifests in mixing of chiral pairs
 - Dileptons give direct access to the chiral mixing
- Is there a first order phase transition? No measurements in the respective energy

Chiral mixing



Possible phase transition



Fireball development in a heavy ion collision

*arXiv: 1607.01487

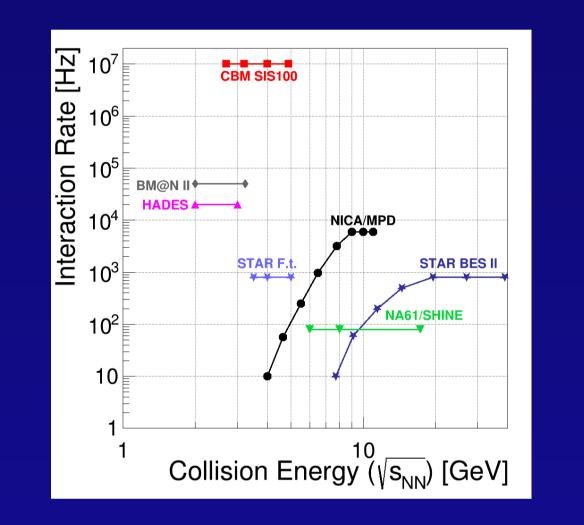
regime

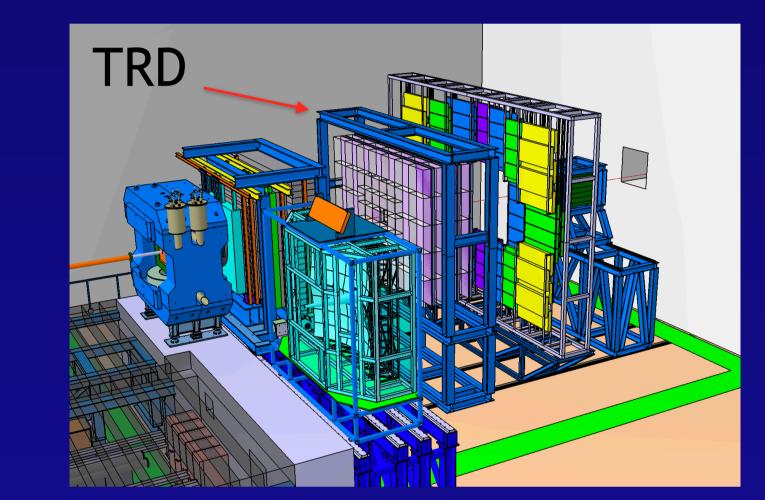
- Dielectrons can be used as thermometer of the emitting source
- They can also be used as chronometer and barometer
- They carry information about the early phases of the fireball

charm Φ, Ξ, Ω Κ, π, Λ, η resonance thermal $\gamma \rightarrow e^+e^-/\mu^+\mu^$ prompt γ decay γ decays

The CBM experiment

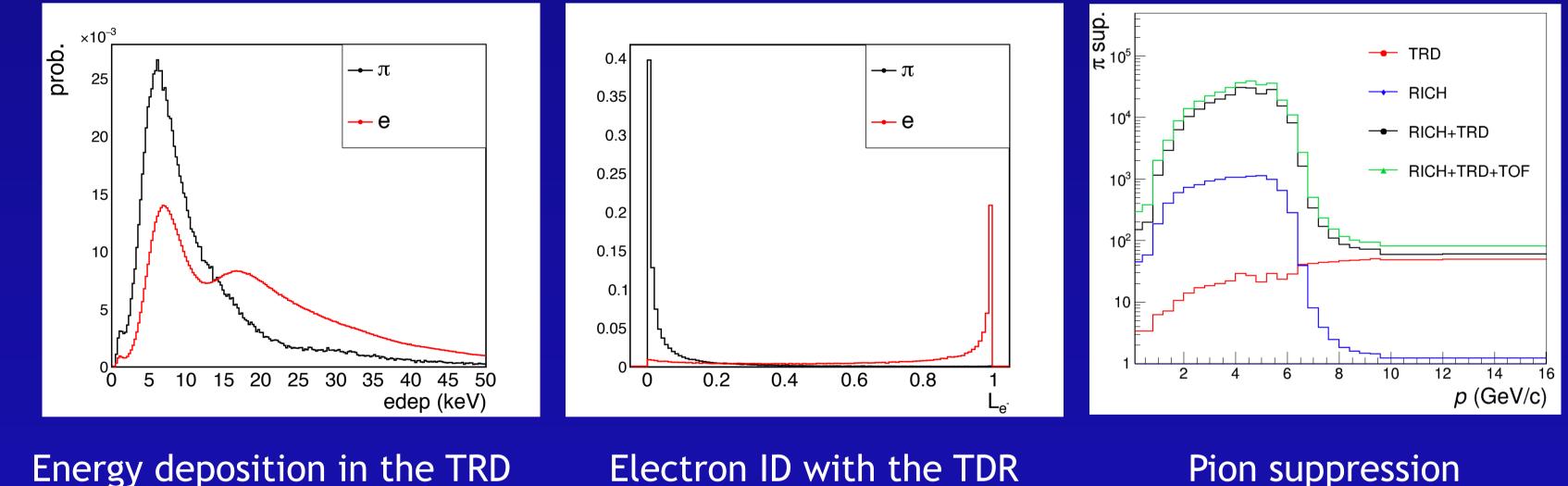
- Unmatched interaction rates at moderate energies Investigation of rare processes
- Interchangable detector configurations
 - Specified for electron / muon / hadron measurements





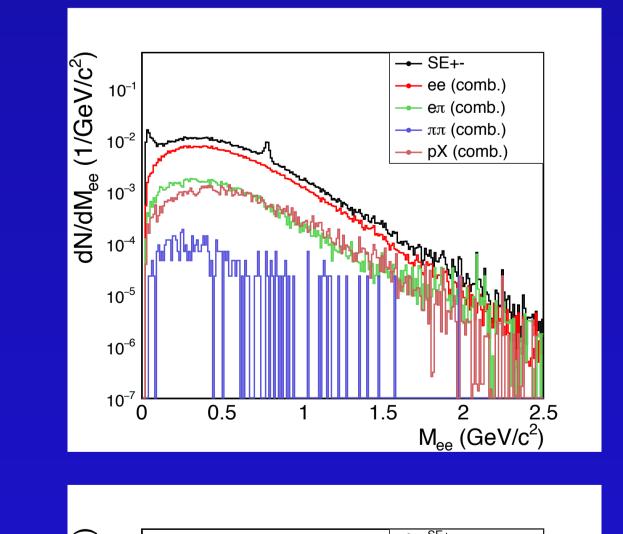
Electron identification with the TRD

- Dielectron channels have very low cross sections There are large hadronic contributions
 - ➡ A good pion suppression is needed
- The RICH detector does not provide electron ID at high momenta
- The electron ID of the TRD increases while the RICH reaches his limits



8 A GeV 10% most centr. Au+Au collisions

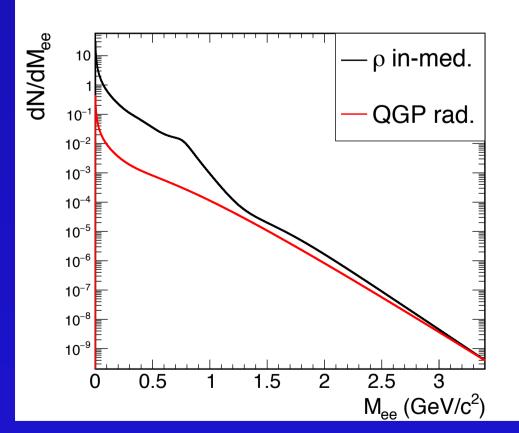
- Combinatorial dielectrons are the dominant background contribution
 - Pion suppression is sufficient in the whole invariant mass



12 A GeV Au+Au outlook

- New theory calculations for thermal radiation at 12 A GeV Fireball model with a coarse-graining approach
- Highest multiplicities

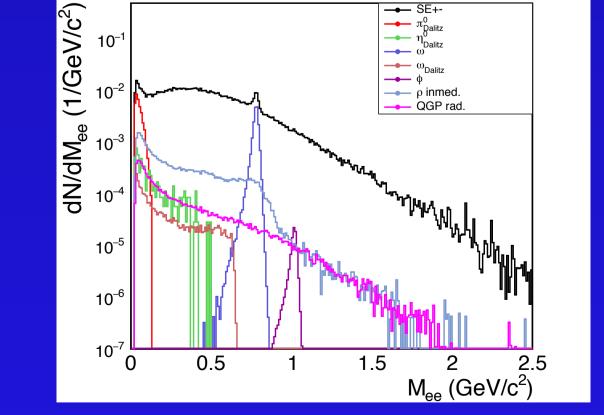
Thermal calculations

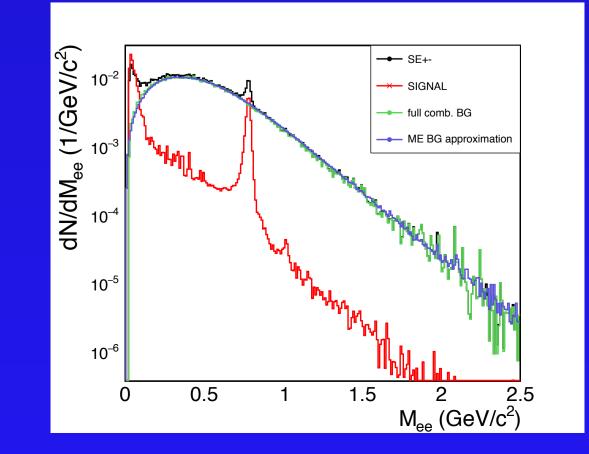


range

- Clear peaks for the low mass vector mesons
- Thermal radiation is the only signal source above 1 GeV

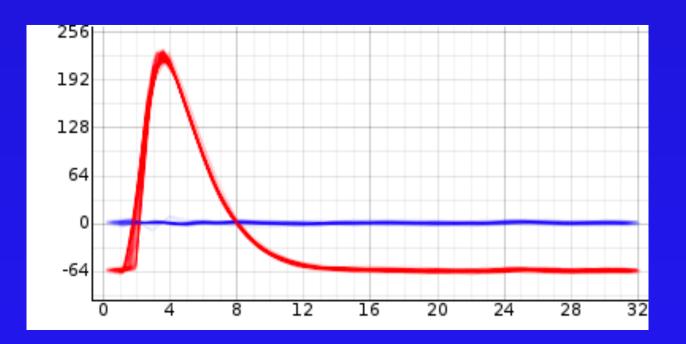






• New detector simulations Final detector geometries Time-based analysis Detailed electronics simulations

Test injection in the chip prototype



* arXiv: 1512.08688

Simulated electronics response

